



NÁRODNÍ AKREDITAČNÍ ORGÁN

EA MLA Signatory  
Český institut pro akreditaci, o.p.s.  
Olšanská 54/3, 130 00 Praha 3

issues

according to section 16 of Act No. 22/1997 Coll., on technical requirements for products, as amended

## CERTIFICATE OF ACCREDITATION

No. 380/2018

**Mitutoyo Česko s.r.o.**  
with registered office Dubská 1626, 415 01 Teplice 1, Company Registration No. 25458400

to the Calibration Laboratory No. 2390  
Calibration Laboratory

Scope of accreditation:

Calibration of coordinate measuring machines (CMM), instruments for the measurement of surface roughness and profile, profile projectors and microscopes to the extent as specified in the appendix to this Certificate.

This Certificate of Accreditation is a proof of Accreditation issued on the basis of assessment of fulfillment of the accreditation criteria in accordance with

ČSN EN ISO/IEC 17025:2005

In its activities performed within the scope and for the period of validity of this Certificate, the Body is entitled to refer to this Certificate, provided that the accreditation is not suspended and the Body meets the specified accreditation requirements in accordance with the relevant regulations applicable to the activity of an accredited Conformity Assessment Body.

This Certificate of Accreditation replaces, to the full extent, Certificate No.: 694/2016 of 8. 12. 2016, or any administrative acts building upon it.

The Certificate of Accreditation is valid until: **8. 12. 2019**

Prague: 13. 7. 2018



Jiří Růžička  
Director  
Czech Accreditation Institute  
Public Service Company



**The Appendix is an integral part of  
Certificate of Accreditation No. 380/2018 of 13/07/2018**

**Accredited entity according to ČSN EN ISO/IEC 17025:2005:**

**Mitutoyo Česko s.r.o.**  
Calibration Laboratory  
Dubská 1626, 415 01 Teplice 1

The Laboratory is qualified to update standards identifying the calibration procedures.

**Field of measured quantity: Length**

**Calibration:**

Nominal calibration temperature:  $(20 \pm 1) ^\circ\text{C}$

Ordinal number <sup>1)</sup>	Measured quantity	Measured quantity range	Calibration and Measurement Capability [ $\pm$ ] <sup>2)</sup>	Calibration procedure identification
1*	Calibration using coordinate measuring machines - by laser interferometer - by step gage - by reference ball	(0 to 5) m (0 to 1.5) m	(0.1 + 0.3L) $\mu\text{m}$ (0.3 + 0.6L) $\mu\text{m}$ 0.2 $\mu\text{m}$	MCZ-PI-KL_SD15_KP01 (ČSN EN ISO 10360-2, ČSN EN ISO 10360-4, ČSN EN ISO 10360-5)
2*	Calibration of surface roughness measuring instruments Ra Rz Rsm Linearity error Straightness error	(0.1 to 50) $\mu\text{m}$ (0.01 to 50) $\mu\text{m}$ (0.1 to 400) $\mu\text{m}$ (-400 to 400) $\mu\text{m}$ -	3.4 % 2.4 % 0.6 % 4 $\mu\text{m}$ 0.06 $\mu\text{m}$	MCZ-PI-KL_SD15_KP02 (ČSN EN ISO 3274, ČSN EN ISO 12179)
3*	Calibration of surface profile measuring instruments Length measurement error Straightness measurement error Angle error	X, Y = 200 mm Z = 60 mm - 135 °	(0.2+0.3L) $\mu\text{m}$ 0.06 $\mu\text{m}$ 0.0034 °	MCZ-PI-KL_SD15_KP02 (ČSN EN ISO 3274, ČSN EN ISO 12179)
4*	Calibration of profile projectors Length measurement error Parallelity P <sub>XY</sub> Cross hair position E <sub>CH</sub> Magnification error Focus screen rotation  Calibration of measuring microscopes Length measurement error Parallelity P <sub>XY</sub>	(0 to 200) mm - - - 360 °  (0 to 400) mm -	(1.2+8.9L) $\mu\text{m}$ 1 $\mu\text{m}$ 4 $\mu\text{m}$ 0.01 % 0.5 '  (1.2+8.9L) $\mu\text{m}$ 1 $\mu\text{m}$	MCZ-PI-KL_SD15_KP03

<sup>1)</sup> Asterisk at the ordinal number identifies the calibrations, which the Laboratory is qualified to carry out outside the permanent laboratory premises.

<sup>2)</sup> Expressed like uncertainty in accordance with the requirements of the document EA 4/02 at k = 2.

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Explanations:

L – Length in metres

Parallelity PXY – Parallelity of a cross table with a cross hair PXY

MCZ-PI-KL\_SD15 KP xx – Internal Calibration Procedure

**Measured instruments or devices:**

(In accordance with the above list of measured quantities and the ranges of measurement the following types of instruments or devices can be measured.)

Ordinal number	Measured instrument/device type
1	Coordinate measuring machines (CMM) Mitutoyo – touch-trigger, touch-scan systems
2	Surface roughness measuring instruments, roughness meters, combined surface roughness and profile measuring instruments
3	Profile (shape) measuring instruments, contourographs, combined surface roughness and profile measuring instruments
4	Profile projectors and measuring microscopes

